## Application/Control No. Applicant(s)/Patent Under Reexamination 09/910,709 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Olisa Anwah 2645 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 05-2003 US-6,570,080 Hasegawa et al. 84/609 Α US-2002/0023099 02-2002 В Wendelrup, Heino 707/200 US-2005/0223224 10-2005 Carpentier et al. 713/165 С D US-US-Е US-F US-G US-Н US-US-J K US-US-L М US-**FOREIGN PATENT DOCUMENTS Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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